

<b>Notice of References Cited</b>	Application/Control No. 10/017,021	Applicant(s)/Patent Under Reexamination YUTKOWITZ, STEPHEN J.	
	Examiner Joshua C Liu	Art Unit 2121	Page 1 of 1

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*	B	US-2003/0045949	03-2003	Stone et al.	700/61
*	C	US-4,623,971	11-1986	Ailman et al.	700/252
*	D	US-3,798,430	03-1974	Simon et al.	318/571
*	E	US-5,285,378	02-1994	Matsumoto, Kouki	700/37
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.